

Diode EMCON 4 Medium Power Chip

FEATURES:

- 1200V EMCON 4 technology
- soft, fast switching
- low reverse recovery charge
- small temperature coefficient

This chip is used for:

• low / medium power modules



Applications:

• low / medium power drives

Chip Type	V_R	I _F	Die Size	Package		
IDC21D120T6M	1200V	35A	3.40 x 6.25 mm ²	sawn on foil		

MECHANICAL PARAMETER:

Raster size	3.40 x 6.25			
		2		
Area total / active	21.25 / 13.97	mm ²		
Anode pad size	2.446 x 5.296			
Thickness	110	μm		
Wafer size	150	mm		
Flat position	180	deg		
Max. possible chips per wafer	693 pcs			
Passivation frontside	tside Photoimide			
Pad metall	3200 nm AlSiCu			
Backside metall	Ni Ag –system suitable for epoxy and soft solder die bonding			
Die bond	electrically conductive glue or solder			
Wire bond	AI, ≤500μm			
Reject ink dot size	Ø 0.65mm; max 1.2mm			
Recommended storage environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



Maximum Ratings

Parameter	Symbol Condition		Value	Unit	
Repetitive peak reverse voltage	V_{RRM}		1200	V	
Continuous forward current limited by	,		1)		
T _{jmax}	I _F			Α	
Maximum repetitive forward current	1		70		
limited by T _{jmax}	/ _{FRM}		70		
Maximum junction and storage temperature	$T_{\rm vj,max}$, $T_{\rm stg}$		-40+175	°C	
Reverse bias safe operating area ²⁾ (RBSOA)	$I_{F,max} = 70A$, $V_{R,max} = 1200V$, $T_{vj,op} \le 150$ °C, $P_{max} = $ tbd kW				

¹⁾ depending on thermal properties of assembly

Static Electrical Characteristics (tested on wafer), T_i =25 °C

Parameter	Symbol	Condi	Value			Unit	
raiailletei	Symbol	Conditions		min.	Тур.	max.	John
Reverse leakage current	I_{R}	V _R =1200V	T _j =25°C			7.7	μΑ
Cathode-Anode breakdown Voltage	V _{Br}	I _R =0.25mA	<i>T_j</i> =25°C	1200			V
Forward voltage drop	V_{F}	I _F =35A	<i>T_j</i> =25 °C	1.35	1.7	2.05	V

Dynamic Electrical Characteristics inductive load (not subject to production test - verified by design/characterization)

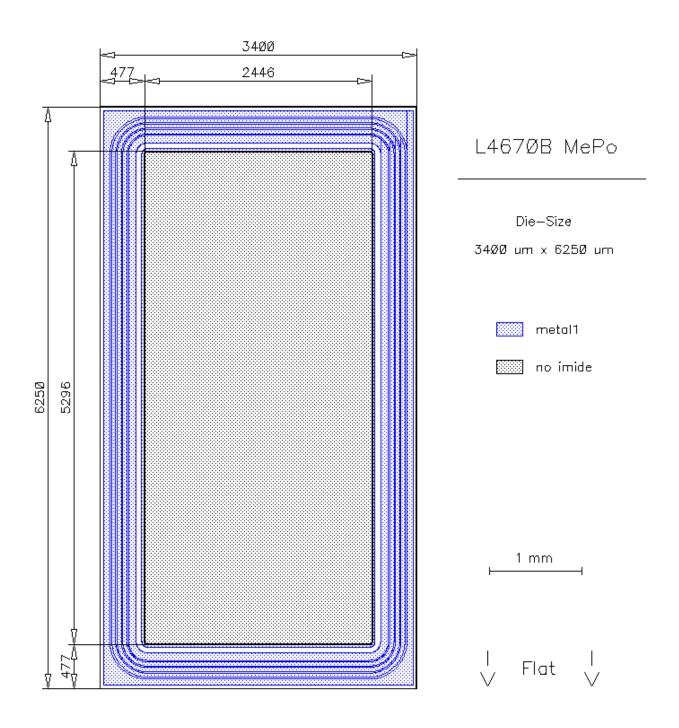
Parameter	Symbol	Conditions		Value 2)			Unit
rarameter	Symbol			min.	Тур.	max.	Julit
Peak reverse recovery current	I _{RM}	$I_F=A$ di/dt=A/ms $V_R=V$ $V_{GE}=-15V$	$T_j = 25 ^{\circ}\text{C}$ $T_j = 125 ^{\circ}\text{C}$ $T_j = 150 ^{\circ}\text{C}$		tbd		А
Reverse recovery charge	Q _r	$I_F=A$ di/dt=A/ms $V_R=V$ $V_{GE}=-15V$	$T_j = 25 ^{\circ}\text{C}$ $T_j = 125 ^{\circ}\text{C}$ $T_j = 150 ^{\circ}\text{C}$		tbd		μC
Reverse recovery energy	E _{rec}	$I_F=A$ di/dt=A/ms $V_R=V$ $V_{GE}=-15V$	$T_j = 25 ^{\circ}\text{C}$ $T_j = 125 ^{\circ}\text{C}$ $T_j = 150 ^{\circ}\text{C}$		tbd		mJ

 $^{^{2)}}$ values also influenced by parasitic L- and C- in measurement and package.

²⁾ not subject to production test - verified by design/characterisation



CHIP DRAWING:





This chip data sheet refers to the device data sheet Description: AQL 0,65 for visual inspection according to failure catalog Electrostatic Discharge Sensitive Device according to MIL-STD 883 Test-Normen Villach/Prüffeld

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